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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8543ehxaqg

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

 Performance monitor facility that is similar to, but separate from, the device performance monitor

The e500 defines features that are not implemented on this device. It also generally defines some features that this device implements more specifically. An understanding of these differences can be critical to ensure proper operations.

- 512-Kbyte L2 cache/SRAM
 - Flexible configuration.
 - Full ECC support on 64-bit boundary in both cache and SRAM modes
 - Cache mode supports instruction caching, data caching, or both.
 - External masters can force data to be allocated into the cache through programmed memory ranges or special transaction types (stashing).
 - 1, 2, or 4 ways can be configured for stashing only.
 - Eight-way set-associative cache organization (32-byte cache lines)
 - Supports locking entire cache or selected lines. Individual line locks are set and cleared through Book E instructions or by externally mastered transactions.
 - Global locking and Flash clearing done through writes to L2 configuration registers
 - Instruction and data locks can be Flash cleared separately.
 - SRAM features include the following:
 - I/O devices access SRAM regions by marking transactions as snoopable (global).
 - Regions can reside at any aligned location in the memory map.
 - Byte-accessible ECC is protected using read-modify-write transaction accesses for smaller-than-cache-line accesses.
- Address translation and mapping unit (ATMU)
 - Eight local access windows define mapping within local 36-bit address space.
 - Inbound and outbound ATMUs map to larger external address spaces.
 - Three inbound windows plus a configuration window on PCI/PCI-X and PCI Express
 - − Four inbound windows plus a default window on RapidIOTM
 - Four outbound windows plus default translation for PCI/PCI-X and PCI Express
 - Eight outbound windows plus default translation for RapidIO with segmentation and sub-segmentation support
- DDR/DDR2 memory controller
 - Programmable timing supporting DDR and DDR2 SDRAM
 - 64-bit data interface
 - Four banks of memory supported, each up to 4 Gbytes, to a maximum of 16 Gbytes
 - DRAM chip configurations from 64 Mbits to 4 Gbits with ×8/×16 data ports
 - Full ECC support
 - Page mode support
 - Up to 16 simultaneous open pages for DDR

Overview

- Up to 32 simultaneous open pages for DDR2
- Contiguous or discontiguous memory mapping
- Read-modify-write support for RapidIO atomic increment, decrement, set, and clear transactions
- Sleep mode support for self-refresh SDRAM
- On-die termination support when using DDR2
- Supports auto refreshing
- On-the-fly power management using CKE signal
- Registered DIMM support
- Fast memory access via JTAG port
- 2.5-V SSTL_2 compatible I/O (1.8-V SSTL_1.8 for DDR2)
- Support for battery-backed main memory
- Programmable interrupt controller (PIC)
 - Programming model is compliant with the OpenPIC architecture.
 - Supports 16 programmable interrupt and processor task priority levels
 - Supports 12 discrete external interrupts
 - Supports 4 message interrupts with 32-bit messages
 - Supports connection of an external interrupt controller such as the 8259 programmable interrupt controller
 - Four global high-resolution timers/counters that can generate interrupts
 - Supports a variety of other internal interrupt sources
 - Supports fully nested interrupt delivery
 - Interrupts can be routed to external pin for external processing.
 - Interrupts can be routed to the e500 core's standard or critical interrupt inputs.
 - Interrupt summary registers allow fast identification of interrupt source.
- Integrated security engine (SEC) optimized to process all the algorithms associated with IPSec, IKE, WTLS/WAP, SSL/TLS, and 3GPP
 - Four crypto-channels, each supporting multi-command descriptor chains
 - Dynamic assignment of crypto-execution units via an integrated controller
 - Buffer size of 256 bytes for each execution unit, with flow control for large data sizes
 - PKEU—public key execution unit
 - RSA and Diffie-Hellman; programmable field size up to 2048 bits
 - Elliptic curve cryptography with F_2m and F(p) modes and programmable field size up to 511 bits
 - DEU—Data Encryption Standard execution unit
 - DES, 3DES
 - Two key (K1, K2) or three key (K1, K2, K3)
 - ECB and CBC modes for both DES and 3DES

Overview

- Memory prefetching of PCI read accesses
- Supports posting of processor-to-PCI and PCI-to-memory writes
- PCI 3.3-V compatible
- Selectable hardware-enforced coherency
- Serial RapidIO[™] interface unit
 - Supports RapidIO[™] Interconnect Specification, Revision 1.2
 - Both $1 \times$ and $4 \times$ LP-serial link interfaces
 - Long- and short-haul electricals with selectable pre-compensation
 - Transmission rates of 1.25, 2.5, and 3.125 Gbaud (data rates of 1.0, 2.0, and 2.5 Gbps) per lane
 - Auto detection of 1- and 4-mode operation during port initialization
 - Link initialization and synchronization
 - Large and small size transport information field support selectable at initialization time
 - 34-bit addressing
 - Up to 256 bytes data payload
 - All transaction flows and priorities
 - Atomic set/clr/inc/dec for read-modify-write operations
 - Generation of IO_READ_HOME and FLUSH with data for accessing cache-coherent data at a remote memory system
 - Receiver-controlled flow control
 - Error detection, recovery, and time-out for packets and control symbols as required by the RapidIO specification
 - Register and register bit extensions as described in part VIII (Error Management) of the RapidIO specification
 - Hardware recovery only
 - Register support is not required for software-mediated error recovery.
 - Accept-all mode of operation for fail-over support
 - Support for RapidIO error injection
 - Internal LP-serial and application interface-level loopback modes
 - Memory and PHY BIST for at-speed production test
- RapidIO-compatible message unit
 - 4 Kbytes of payload per message
 - Up to sixteen 256-byte segments per message
 - Two inbound data message structures within the inbox
 - Capable of receiving three letters at any mailbox
 - Two outbound data message structures within the outbox
 - Capable of sending three letters simultaneously
 - Single segment multicast to up to 32 devIDs
 - Chaining and direct modes in the outbox

4.5 Platform to FIFO Restrictions

Note the following FIFO maximum speed restrictions based on platform speed.

For FIFO GMII mode:

FIFO TX/RX clock frequency ≤ platform clock frequency/4.2

For example, if the platform frequency is 533 MHz, the FIFO TX/RX clock frequency must be no more than 127 MHz.

For FIFO encoded mode:

FIFO TX/RX clock frequency \leq platform clock frequency/4.2

For example, if the platform frequency is 533 MHz, the FIFO TX/RX clock frequency must be no more than 167 MHz.

4.6 Platform Frequency Requirements for PCI-Express and Serial RapidIO

The CCB clock frequency must be considered for proper operation of the high-speed PCI-Express and Serial RapidIO interfaces as described below.

For proper PCI Express operation, the CCB clock frequency must be greater than:

See *MPC8548ERM*, *Rev.* 2, *PowerQUICC III Integrated Processor Family Reference Manual*, Section 18.1.3.2, "Link Width," for PCI Express interface width details.

For proper serial RapidIO operation, the CCB clock frequency must be greater than:

 $2 \times (0.80) \times (Serial RapidIO interface frequency) \times (Serial RapidIO link width)$

64

See *MPC8548ERM*, *Rev.* 2, *PowerQUICC III Integrated Processor Family Reference Manual*, Section 17.4, "1x/4x LP-Serial Signal Descriptions," for serial RapidIO interface width and frequency details.

4.7 Other Input Clocks

For information on the input clocks of other functional blocks of the platform see the specific section of this document.

Table 13 provides the recommended operating conditions for the DDR SDRAM controller when $GV_{DD}(typ) = 2.5 \text{ V}.$

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	GV _{DD}	2.375	2.625	V	1
I/O reference voltage	MV _{REF}	$0.49 \times GV_{DD}$	$0.51 \times GV_{DD}$	V	2
I/O termination voltage	V _{TT}	MV _{REF} – 0.04	MV _{REF} + 0.04	V	3
Input high voltage	V _{IH}	MV _{REF} + 0.15	GV _{DD} + 0.3	V	—
Input low voltage	V _{IL}	-0.3	MV _{REF} – 0.15	V	—
Output leakage current	I _{OZ}	-50	50	μA	4
Output high current (V _{OUT} = 1.95 V)	I _{OH}	-16.2	—	mA	—
Output low current ($V_{OUT} = 0.35 V$)	I _{OL}	16.2	—	mA	—

Table 13	DDR SDRAM	DC Electrical	Characteristics	for GV	(tvn) = 2	25 V
Table 15.	DDIX SDIXAM		Gilaracteristics		(()) – 4	1.J V

Notes:

1. ${\rm GV}_{\rm DD}$ is expected to be within 50 mV of the DRAM ${\rm V}_{\rm DD}$ at all times.

2. MV_{REF} is expected to be equal to 0.5 × GV_{DD}, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MV_{REF} may not exceed ±2% of the DC value.

3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MV_{REF}. This rail must track variations in the DC level of MV_{REF}.

4. Output leakage is measured with all outputs disabled, 0 V \leq V_{OUT} \leq GV_{DD}.

Table 14 provides the DDR I/O capacitance when $GV_{DD}(typ) = 2.5$ V.

Table 14. DDR SDRAM Capacitance for GV_{DD}(typ) = 2.5 V

Parameter/Condition	Symbol	Min	Мах	Unit	Notes
Input/output capacitance: DQ, DQS	C _{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS	C _{DIO}	—	0.5	pF	1

Note:

1. This parameter is sampled. $GV_{DD} = 2.5 \text{ V} \pm 0.125 \text{ V}$, f = 1 MHz, T_A = 25°C, $V_{OUT} = GV_{DD}/2$, V_{OUT} (peak-to-peak) = 0.2 V.

This table provides the current draw characteristics for MV_{REF}.

Table 15. Current Draw Characteristics for MV_{REF}

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Current draw for MV _{REF}	I _{MVREF}		500	μA	1

Note:

1. The voltage regulator for MV_{REF} must be able to supply up to 500 μ A current.

8 Enhanced Three-Speed Ethernet (eTSEC)

This section provides the AC and DC electrical characteristics for the enhanced three-speed Ethernet controller. The electrical characteristics for MDIO and MDC are specified in Section 9, "Ethernet Management Interface Electrical Characteristics."

8.1 Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1Gb Mbps)—GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics

The electrical characteristics specified here apply to all gigabit media independent interface (GMII), media independent interface (MII), ten-bit interface (TBI), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), and reduced media independent interface (RMII) signals except management data input/output (MDIO) and management data clock (MDC). The RGMII and RTBI interfaces are defined for 2.5 V, while the GMII, MII, and TBI interfaces can be operated at 3.3 or 2.5 V. The GMII, MII, or TBI interface timing is compliant with the IEEE 802.3. The RGMII and RTBI interfaces follow the *Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3* (12/10/2000). The RMII interface follows the *RMII Consortium RMII Specification Version 1.2* (3/20/1998). The electrical characteristics for MDIO and MDC are specified in Section 9, "Ethernet Management Interface Electrical Characteristics."

8.1.1 eTSEC DC Electrical Characteristics

All GMII, MII, TBI, RGMII, RMII, and RTBI drivers and receivers comply with the DC parametric attributes specified in Table 22 and Table 23. The RGMII and RTBI signals are based on a 2.5-V CMOS interface voltage as defined by JEDEC EIA/JESD8-5.

Parameter	Symbol	Min	Мах	Unit	Notes
Supply voltage 3.3 V	LV _{DD} TV _{DD}	3.13	3.47	V	1, 2
Output high voltage ($LV_{DD}/TV_{DD} = min$, $I_{OH} = -4.0 mA$)	V _{OH}	2.40	$LV_{DD}/TV_{DD} + 0.3$	V	_
Output low voltage ($LV_{DD}/TV_{DD} = min, I_{OL} = 4.0 mA$)	V _{OL}	GND	0.50	V	_
Input high voltage	V _{IH}	2.0	$LV_{DD}/TV_{DD} + 0.3$	V	_
Input low voltage	V _{IL}	-0.3	0.90	V	_
Input high current ($V_{IN} = LV_{DD}$, $V_{IN} = TV_{DD}$)	I _{IH}	—	40	μΑ	1, 2, 3
Input low current (V _{IN} = GND)	I	-600	_	μA	

Table 22.	GMII. MI	I. RMII. a	and TBI DC	Electrical	Characteristics
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Notes:

1. LV_{DD} supports eTSECs 1 and 2.

2. TV_DD supports eTSECs 3 and 4.

3. The symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbols referenced in Table 1 and Table 2.

Enhanced Three-Speed Ethernet (eTSEC)

Figure 10 shows the GMII receive AC timing diagram.



Figure 10. GMII Receive AC Timing Diagram

8.2.3 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

8.2.3.1 MII Transmit AC Timing Specifications

This table provides the MII transmit AC timing specifications.

fable 2	28.	MII	Transmit	AC	Timing	Specifications
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Parameter/Condition	Symbol ¹	Min	Тур	Max	Unit
TX_CLK clock period 10 Mbps	t _{MTX} ²	_	400	_	ns
TX_CLK clock period 100 Mbps	t _{MTX}		40	_	ns
TX_CLK duty cycle	t _{MTXH} /t _{MTX}	35	_	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t _{MTKHDX}	1	5	15	ns
TX_CLK data clock rise (20%–80%)	t _{MTXR} ²	1.0	_	4.0	ns
TX_CLK data clock fall (80%–20%)	t _{MTXF} ²	1.0		4.0	ns

Notes:

The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
</sub>

2. Guaranteed by design.

Figure 11 shows the MII transmit AC timing diagram.



Figure 11. MII Transmit AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

This table provides the MII receive AC timing specifications.

Table 29. MII Receive A	C Timing Specifications
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Parameter/Condition	Symbol ¹	Min	Тур	Max	Unit
RX_CLK clock period 10 Mbps	t _{MRX} ²	_	400	—	ns
RX_CLK clock period 100 Mbps	t _{MRX}	—	40	—	ns
RX_CLK duty cycle	t _{MRXH} /t _{MRX}	35	_	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t _{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t _{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise (20%–80%)	t _{MRXR} ²	1.0	—	4.0	ns
RX_CLK clock fall time (80%–20%)	t _{MRXF} ²	1.0	_	4.0	ns

Notes:

1. The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).}

2. Guaranteed by design.

Figure 12 provides the AC test load for eTSEC.



Figure 12. eTSEC AC Test Load

Enhanced Three-Speed Ethernet (eTSEC)

Figure 19 provides the AC test load for eTSEC.



Figure 19. eTSEC AC Test Load

Figure 20 shows the RMII receive AC timing diagram.



Figure 20. RMII Receive AC Timing Diagram

l²C

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the device.

13.1 I²C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I^2C interfaces.

Table 45. I²C DC Electrical Characteristics

Parameter	Symbol	Min	Мах	Unit	Notes
Input high voltage level	V _{IH}	$0.7 \times OV_{DD}$	OV _{DD} + 0.3	V	_
Input low voltage level	V _{IL}	-0.3	$0.3\times\text{OV}_{\text{DD}}$	V	
Low level output voltage	V _{OL}	0	$0.2\times \text{OV}_{\text{DD}}$	V	1
Pulse width of spikes which must be suppressed by the input filter	t _{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between $0.1 \times OV_{DD}$ and $0.9 \times OV_{DD}$ (max)	I	-10	10	μA	3
Capacitance for each I/O pin	CI		10	pF	_

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.

- 2. See the MPC8548E PowerQUICC[™] III Integrated Processor Family Reference Manual, for information on the digital filter used.
- 3. I/O pins obstruct the SDA and SCL lines if $\ensuremath{\mathsf{OV}_{\mathsf{DD}}}$ is switched off.

13.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I^2C interfaces.

Table 46. I²C AC Electrical Specifications

Parameter	Symbol ¹	Min	Мах	Unit	Notes
SCL clock frequency	f _{I2C}	0	400	kHz	—
Low period of the SCL clock	t _{I2CL}	1.3	—	μS	4
High period of the SCL clock	t _{I2CH}	0.6	—	μS	4
Setup time for a repeated START condition	t _{I2SVKH}	0.6	—	μS	4
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t _{I2SXKL}	0.6	—	μs	4
Data setup time	t _{I2DVKH}	100	—	ns	4
Data input hold time: CBUS compatible masters I ² C bus devices	t _{I2DXKL}	0		μS	2
Data output delay time:	t _{I2OVKL}	—	0.9	—	3
Set-up time for STOP condition	t _{I2PVKH}	0.6	—	μs	—
Bus free time between a STOP and START condition	t _{I2KHDX}	1.3	—	μS	

Table 53. PCI-X AC Timing Specifications at 66 MHz (continued)

Parameter	Symbol	Min	Max	Unit	Notes
HRESET to PCI-X initialization pattern hold time	t _{PCRHIX}	0	50	ns	6, 11

Notes:

- 1. See the timing measurement conditions in the PCI-X 1.0a Specification.
- 2. Minimum times are measured at the package pin (not the test point). Maximum times are measured with the test point and load circuit.
- 3. Setup time for point-to-point signals applies to REQ and GNT only. All other signals are bused.
- 4. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- 5. Setup time applies only when the device is not driving the pin. Devices cannot drive and receive signals at the same time.
- 6. Maximum value is also limited by delay to the first transaction (time for HRESET high to first configuration access, t_{PCRHFV}). The PCI-X initialization pattern control signals after the rising edge of HRESET must be negated no later than two clocks before the first FRAME and must be floated no later than one clock before FRAME is asserted.
- 7. A PCI-X device is permitted to have the minimum values shown for t_{PCKHOV} and t_{CYC} only in PCI-X mode. In conventional mode, the device must meet the requirements specified in PCI 2.2 for the appropriate clock frequency.
- 8. Device must meet this specification independent of how many outputs switch simultaneously.

9. The timing parameter t_{PCRHFV} is a minimum of 10 clocks rather than the minimum of 5 clocks in the PCI-X 1.0a Specification.

10.Guaranteed by characterization.

11.Guaranteed by design.

This table provides the PCI-X AC timing specifications at 133 MHz. Note that the maximum PCI-X frequency in synchronous mode is 110 MHz.

Parameter	Symbol	Min	Max	Unit	Notes
SYSCLK to signal valid delay	^t PCKHOV		3.8	ns	1, 2, 3, 7, 8
Output hold from SYSCLK	t _{PCKHOX}	0.7	_	ns	1, 11
SYSCLK to output high impedance	t _{PCKHOZ}		7	ns	1, 4, 8, 12
Input setup time to SYSCLK	t _{PCIVKH}	1.2	_	ns	3, 5, 9, 11
Input hold time from SYSCLK	t _{PCIXKH}	0.5	_	ns	11
REQ64 to HRESET setup time	t _{PCRVRH}	10	_	clocks	12
HRESET to REQ64 hold time	t _{PCRHRX}	0	50	ns	12
HRESET high to first FRAME assertion	t _{PCRHFV}	10	_	clocks	10, 12
PCI-X initialization pattern to HRESET setup time	^t PCIVRH	10	_	clocks	12

Table 54. PCI-X AC Timing Specifications at 133 MHz

High-Speed Serial Interfaces (HSSI)







Figure 42. Single-Ended Reference Clock Input DC Requirements

16.2.3 Interfacing with Other Differential Signaling Levels

- With on-chip termination to SGND_SRDSn (xcorevss), the differential reference clocks inputs are HCSL (high-speed current steering logic) compatible DC-coupled.
- Many other low voltage differential type outputs like LVDS (low voltage differential signaling) can be used but may need to be AC-coupled due to the limited common mode input range allowed (100 to 400 mV) for DC-coupled connection.
- LVPECL outputs can produce signal with too large amplitude and may need to be DC-biased at clock driver output first, then followed with series attenuation resistor to reduce the amplitude, in addition to AC-coupling.

NOTE

Figure 43 through Figure 46 below are for conceptual reference only. Due to the fact that clock driver chip's internal structure, output impedance, and termination requirements are different between various clock driver chip manufacturers, it is very possible that the clock circuit reference designs provided by clock driver chip vendor are different from what is shown below. They might also vary from one vendor to the other. Therefore, Freescale Semiconductor can neither provide the optimal clock driver reference circuits, nor guarantee the correctness of the following clock driver connection reference circuits. The system designer is recommended to contact the selected clock driver chip vendor for the optimal reference circuits with the SerDes reference clock receiver requirement provided in this document.

Package Description

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1_REQ[4:1]	AH2, AG4, AG3, AH4	l	OV _{DD}	—
				_
				_
				_
				_
PCI1_REQ0	AH3	I/O	OV _{DD}	—
PCI1_CLK	AH26	I	OV _{DD}	39
PCI1_DEVSEL	AH11	I/O	OV _{DD}	2
PCI1_FRAME	AE11	I/O	OV _{DD}	2
PCI1_IDSEL	AG9	I	OV _{DD}	—
PCI1_REQ64/PCI2_FRAME	AF14	I/O	OV _{DD}	2, 5, 10
PCI1_ACK64/PCI2_DEVSEL	V15	I/O	OV _{DD}	2
PCI2_CLK	AE28	I	OV _{DD}	39
PCI2_IRDY	AD26	I/O	OV _{DD}	2
PCI2_PERR	AD25	I/O	OV _{DD}	2
PCI2_GNT[4:1]	AE26, AG24, AF25, AE25	0	OV _{DD}	5, 9, 35
PCI2_GNT0	AG25	I/O	OV _{DD}	_
PCI2_SERR	AD24	I/O	OV _{DD}	2, 4
PCI2_STOP	AF24	I/O	OV _{DD}	2
PCI2_TRDY	AD27	I/O	OV _{DD}	2
PCI2_REQ[4:1]	AD28, AE27, W17, AF26	I	OV _{DD}	—
PCI2_REQ0	AH25	I/O	OV _{DD}	—
	DDR SDRAM Memory Interface			
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV _{DD}	
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV _{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	0	GV _{DD}	
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV _{DD}	_
MDQS[0:8]	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV _{DD}	_
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	0	GV _{DD}	_
MBA[0:2]	F7, J7, M11	0	GV _{DD}	_

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SENSEVSS	M16	—	—	13
	Analog Signals			
MVREF	A18	I Reference voltage signal for DDR	MVREF	
SD_IMP_CAL_RX	L28	I	200Ω to GND	_
SD_IMP_CAL_TX	AB26	I	100Ω to GND	
SD_PLL_TPA	U26	0	—	24

Table 71. MPC8548E Pinout Listing (continued)

Notes:

1. All multiplexed signals are listed only once and do not re-occur. For example, LCS5/DMA_REQ2 is listed only once in the local bus controller section, and is not mentioned in the DMA section even though the pin also functions as DMA_REQ2.

- 2. Recommend a weak pull-up resistor (2-10 kΩ) be placed on this pin to OV_{DD}.
- 3. A valid clock must be provided at POR if TSEC4_TXD[2] is set = 1.
- 4. This pin is an open drain signal.
- 5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pullup or active driver is needed.
- 6. Treat these pins as no connects (NC) unless using debug address functionality.
- The value of LA[28:31] during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See Section 20.2, "CCB/SYSCLK PLL Ratio."
- 8. The value of LALE, LGPL2, and LBCTL at reset set the e500 core clock to CCB clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the Section 20.3, "e500 Core PLL Ratio."
- 9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin therefore is described as an I/O for boundary scan.
- 10. This pin functionally requires a pull-up resistor, but during reset it is a configuration input that controls 32- vs. 64-bit PCI operation. Therefore, it must be actively driven low during reset by reset logic if the device is to be configured to be a 64-bit PCI device. See the *PCI Specification*.
- 11. This output is actively driven during reset rather than being three-stated during reset.
- 12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
- 13. These pins are connected to the V_{DD}/GND planes internally and may be used by the core power supply to improve tracking and regulation.
- 14.Internal thermally sensitive resistor.
- 15.No connections must be made to these pins if they are not used.
- 16. These pins are not connected for any use.
- 17.PCI specifications recommend that a weak pull-up resistor (2–10 kΩ) be placed on the higher order pins to OV_{DD} when using 64-bit buffer mode (pins PCI_AD[63:32] and PCI1_C_BE[7:4]).
- 19.If this pin is connected to a device that pulls down during reset, an external pull-up is required to drive this pin to a safe state during reset.
- 20. This pin is only an output in FIFO mode when used as Rx flow control.

24.Do not connect.

Package Description

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI1_FRAME	AE11	I/O	OV _{DD}	2
PCI1_IDSEL	AG9	I	OV _{DD}	_
PCI1_REQ64/PCI2_FRAME	AF14	I/O	OV _{DD}	2, 5, 10
PCI1_ACK64/PCI2_DEVSEL	V15	I/O	OV _{DD}	2
PCI2_CLK	AE28	I	OV _{DD}	39
PCI2_IRDY	AD26	I/O	OV _{DD}	2
PCI2_PERR	AD25	I/O	OV _{DD}	2
PCI2_GNT[4:1]	AE26, AG24, AF25, AE25	0	OV _{DD}	5, 9, 35
PCI2_GNT0	AG25	I/O	OV _{DD}	_
PCI2_SERR	AD24	I/O	OV _{DD}	2,4
PCI2_STOP	AF24	I/O	OV _{DD}	2
PCI2_TRDY	AD27	I/O	OV _{DD}	2
PCI2_REQ[4:1]	AD28, AE27, W17, AF26	I	OV _{DD}	_
PCI2_REQ0	AH25	I/O	OV _{DD}	_
	DDR SDRAM Memory Interface			
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV _{DD}	
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV _{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	0	GV _{DD}	_
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV _{DD}	_
MDQS[0:8]	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV _{DD}	_
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	Ο	GV _{DD}	—
MBA[0:2]	F7, J7, M11	0	GV _{DD}	_
MWE	E7	0	GV _{DD}	_
MCAS	H7	0	GV _{DD}	_
MRAS	L8	0	GV _{DD}	_
MCKE[0:3]	F10, C10, J11, H11	0	GV _{DD}	11
MCS[0:3]	K8, J8, G8, F8	0	GV _{DD}	_
MCK[0:5]	H9, B15, G2, M9, A14, F1	0	GV _{DD}	_
MCK[0:5]	J9, A15, G1, L9, B14, F2	0	GV _{DD}	
MODT[0:3]	E6, K6, L7, M7	0	GV _{DD}	—

Package Description

Signal	Package Pin Number	Pin Type	Power Supply	Notes	
UDE	AH16	I	OV _{DD}	—	
MCP	AG19	I	OV _{DD}	—	
IRQ[0:7]	AG23, AF18, AE18, AF20, AG18, AF17, AH24, AE20	I	OV _{DD}	_	
IRQ[8]	AF19	I	OV _{DD}	—	
IRQ[9]/DMA_DREQ3	AF21	I	OV _{DD}	1	
IRQ[10]/DMA_DACK3	AE19	I/O	OV _{DD}	1	
IRQ[11]/DMA_DDONE3	AD20	I/O	OV _{DD}	1	
IRQ_OUT	AD18	0	OV _{DD}	2, 4	
	Ethernet Management Interface				
EC_MDC	AB9	0	OV _{DD}	5, 9	
EC_MDIO	AC8	I/O	OV _{DD}	—	
Gigabit Reference Clock					
EC_GTX_CLK125	V11	I	LV _{DD}	—	
Tł	ree-Speed Ethernet Controller (Gigabit Ethern	et 1)	•	•	
TSEC1_RXD[7:0]	R5, U1, R3, U2, V3, V1, T3, T2	I	LV _{DD}	—	
TSEC1_TXD[7:0]	T10, V7, U10, U5, U4, V6, T5, T8	0	LV _{DD}	5, 9	
TSEC1_COL	R4	I	LV _{DD}	—	
TSEC1_CRS	V5	I/O	LV _{DD}	20	
TSEC1_GTX_CLK	U7	0	LV _{DD}	—	
TSEC1_RX_CLK	U3	I	LV _{DD}	—	
TSEC1_RX_DV	V2	I	LV _{DD}	—	
TSEC1_RX_ER	T1	I	LV _{DD}	—	
TSEC1_TX_CLK	Т6	I	LV _{DD}	—	
TSEC1_TX_EN	U9	0	LV _{DD}	30	
TSEC1_TX_ER	Τ7	0	LV _{DD}	—	
GPIN[0:7]	P2, R2, N1, N2, P3, M2, M1, N3	I	LV _{DD}	103	
GPOUT[0:5]	N9, N10, P8, N7, R9, N5	0	LV _{DD}	—	
cfg_dram_type0/GPOUT6	R8	0	LV _{DD}	5, 9	
GPOUT7	N6	0	LV _{DD}	-	
Reserved	P1	_	—	104	
Reserved	R6	_	—	104	
Reserved	P6	_	-	15	
Reserved	N4			105	

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SD_IMP_CAL_RX	L28	Ι	200 Ω to GND	
SD_IMP_CAL_TX	AB26	I	100 Ω to GND	_
SD_PLL_TPA	U26	0		24

Table 73. MPC8545E Pinout Listing (continued)

Note: All note references in this table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 74 provides the pin-out listing for the MPC8543E 783 FC-PBGA package.

NOTE

All note references in the following table use the same numbers as those for Table 71. See Table 71 for the meanings of these notes.

Table 74. MPC8543E Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
	PCI1 (One 32-Bit)			
Reserved	AB14, AC15, AA15, Y16, W16, AB16, AC16, AA16, AE17, AA18, W18, AC17, AD16, AE16, Y17, AC18,	_	_	110
GPOUT[8:15]	AB18, AA19, AB19, AB21, AA20, AC20, AB20, AB22	0	OV _{DD}	—
GPIN[8:15]	AC22, AD21, AB23, AF23, AD23, AE23, AC23, AC24	I	OV _{DD}	111
PCI1_AD[31:0]	AH6, AE7, AF7, AG7, AH7, AF8, AH8, AE9, AH9, AC10, AB10, AD10, AG10, AA10, AH10, AA11, AB12, AE12, AG12, AH12, AB13, AA12, AC13, AE13, Y14, W13, AG13, V14, AH13, AC14, Y15, AB15	I/O	OV _{DD}	17
Reserved	AF15, AD14, AE15, AD15	_	_	110
PCI1_C_BE[3:0]	AF9, AD11, Y12, Y13	I/O	OV _{DD}	17
Reserved	W15	_	_	110
PCI1_GNT[4:1]	AG6, AE6, AF5, AH5	0	OV _{DD}	5, 9, 35
PCI1_GNT0	AG5	I/O	OV _{DD}	—
PCI1_IRDY	AF11	I/O	OV _{DD}	2
PCI1_PAR	AD12	I/O	OV _{DD}	—
PCI1_PERR	AC12	I/O	OV _{DD}	2
PCI1_SERR	V13	I/O	OV _{DD}	2, 4
PCI1_STOP	W12	I/O	OV _{DD}	2

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
MWE	E7	0	GV _{DD}	_
MCAS	H7	0	GV _{DD}	_
MRAS	L8	0	GV _{DD}	
MCKE[0:3]	F10, C10, J11, H11	0	GV _{DD}	11
MCS[0:3]	K8, J8, G8, F8	0	GV _{DD}	
MCK[0:5]	H9, B15, G2, M9, A14, F1	0	GV _{DD}	_
MCK[0:5]	J9, A15, G1, L9, B14, F2	0	GV _{DD}	
MODT[0:3]	E6, K6, L7, M7	0	GV _{DD}	_
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36
	Local Bus Controller Interface			
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	
LA[27]	H21	0	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	0	BV _{DD}	5, 7, 9
LCS[0:4]	J25, C20, J24, G26, A26	0	BV _{DD}	_
LCS5/DMA_DREQ2	D23	I/O	BV _{DD}	1
LCS6/DMA_DACK2	G20	0	BV _{DD}	1
LCS7/DMA_DDONE2	E21	0	BV _{DD}	1
LWE0/LBS0/LSDDQM[0]	G25	0	BV _{DD}	5, 9
LWE1/LBS1/LSDDQM[1]	C23	0	BV _{DD}	5, 9
LWE2/LBS2/LSDDQM[2]	J21	0	BV _{DD}	5, 9
LWE3/LBS3/LSDDQM[3]	A24	0	BV _{DD}	5, 9
LALE	H24	0	BV _{DD}	5, 8, 9
LBCTL	G27	0	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	0	BV _{DD}	5, 9
LGPL1/LSDWE	G22	0	BV _{DD}	5, 9
LGPL2/LOE/LSDRAS	B27	0	BV _{DD}	5, 8, 9
LGPL3/LSDCAS	F24	0	BV _{DD}	5, 9
LGPL4/LGTA/LUPWAIT/LPBSE	H23	I/O	BV _{DD}	
LGPL5	E26	0	BV _{DD}	5, 9
LCKE	E24	0	BV _{DD}	
LCLK[0:2]	E23, D24, H22	0	BV _{DD}	_

Characteristic	JEDEC Board	Symbol	Value	Unit	Notes
Die junction-to-board	N/A	$R_{ extsf{ heta}JB}$	5	°C/W	3
Die junction-to-case	N/A	$R_{ extsf{ heta}JC}$	0.8	°C/W	4

Table 85. Package Thermal Characteristics for FC-PBGA (continued)

Notes:

- 1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.
- 2. Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
- 3. Thermal resistance between the die and the printed circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
- 4. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1). The cold plate temperature is used for the case temperature, measured value includes the thermal resistance of the interface layer.

21.3 Heat Sink Solution

Every system application has different conditions that the thermal management solution must solve. As such, providing a recommended heat sink has not been found to be very useful. When a heat sink is chosen, give special consideration to the mounting technique. Mounting the heat sink to the printed-circuit board is the recommended procedure using a maximum of 10 lbs force (45 Newtons) perpendicular to the package and board. Clipping the heat sink to the package is not recommended.

22 System Design Information

This section provides electrical design recommendations for successful application of the device.

22.1 System Clocking

This device includes five PLLs, as follows:

- 1. The platform PLL generates the platform clock from the externally supplied SYSCLK input. The frequency ratio between the platform and SYSCLK is selected using the platform PLL ratio configuration bits as described in Section 20.2, "CCB/SYSCLK PLL Ratio."
- 2. The e500 core PLL generates the core clock as a slave to the platform clock. The frequency ratio between the e500 core clock and the platform clock is selected using the e500 PLL ratio configuration bits as described in Section 20.3, "e500 Core PLL Ratio."
- 3. The PCI PLL generates the clocking for the PCI bus.
- 4. The local bus PLL generates the clock for the local bus.
- 5. There is a PLL for the SerDes block.

22.2 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD}_PLAT, AV_{DD}_CORE, AV_{DD}_PCI, AV_{DD}_LBIU, and AV_{DD}_SRDS, respectively). The AV_{DD}

System Design Information

The platform PLL ratio and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

22.9 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 63. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

Boundary-scan testing is enabled through the JTAG interface signals. The TRST signal is optional in the IEEE 1149.1 specification, but it is provided on all processors built on Power Architecture technology. The device requires TRST to be asserted during power-on reset flow to ensure that the JTAG boundary logic does not interfere with normal chip operation. While the TAP controller can be forced to the reset state using only the TCK and TMS signals, generally systems assert TRST during the power-on reset flow. Simply tying TRST to HRESET is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP), which implements the debug interface to the chip.

The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert HRESET or TRST in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 63 allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in Figure 62, for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; so emulator vendors have issued many different pin numbering schemes. Some COP headers are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom. Still others number the pins counter-clockwise from pin 1 (as with an IC). Regardless of the numbering scheme, the signal placement recommended in Figure 62 is common to all known emulators.

22.9.1 Termination of Unused Signals

Freescale recommends the following connections, when the JTAG interface and COP header are not used:

• TRST must be tied to HRESET through a 0 k Ω isolation resistor so that it is asserted when the system reset signal (HRESET) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system